## **Power MOSFET** 40 V, 1.2 mΩ, 237 A, Single N–Channel

#### Features

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- NVMFS5C426NLWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

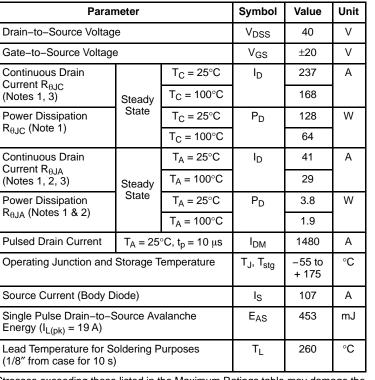
MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

# ON

## **ON Semiconductor®**

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	1.2 mΩ @ 10 V	237 A
40 V	1.8 mΩ @ 4.5 V	231 A



Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

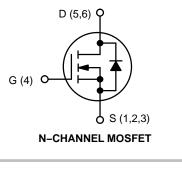
#### THERMAL RESISTANCE MAXIMUM RATINGS

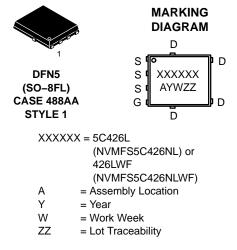
Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	1.2	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\thetaJA}$	39.6	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.

3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.





#### ORDERING INFORMATION

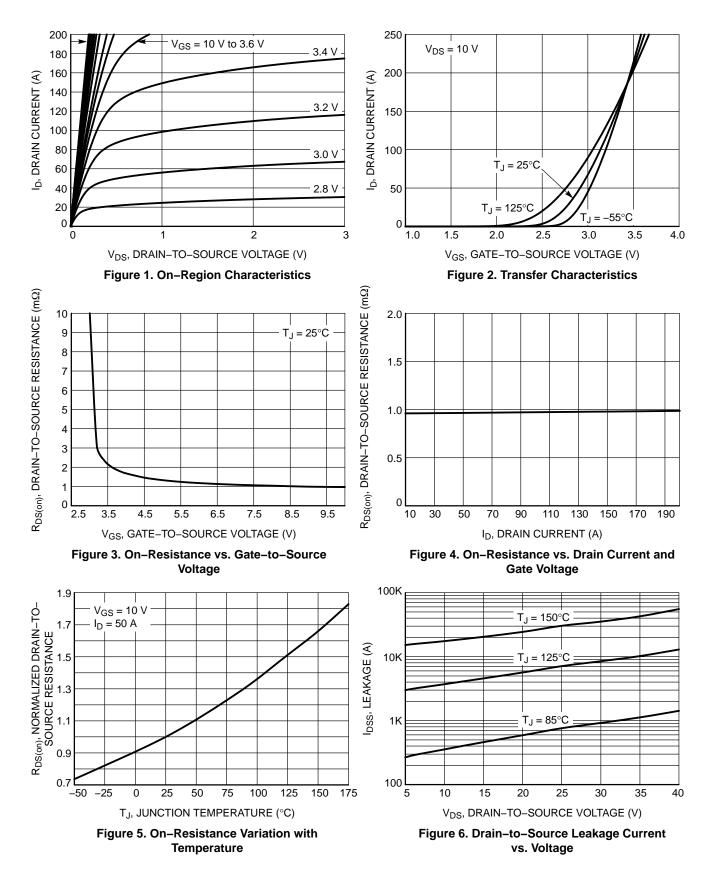
See detailed ordering, marking and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

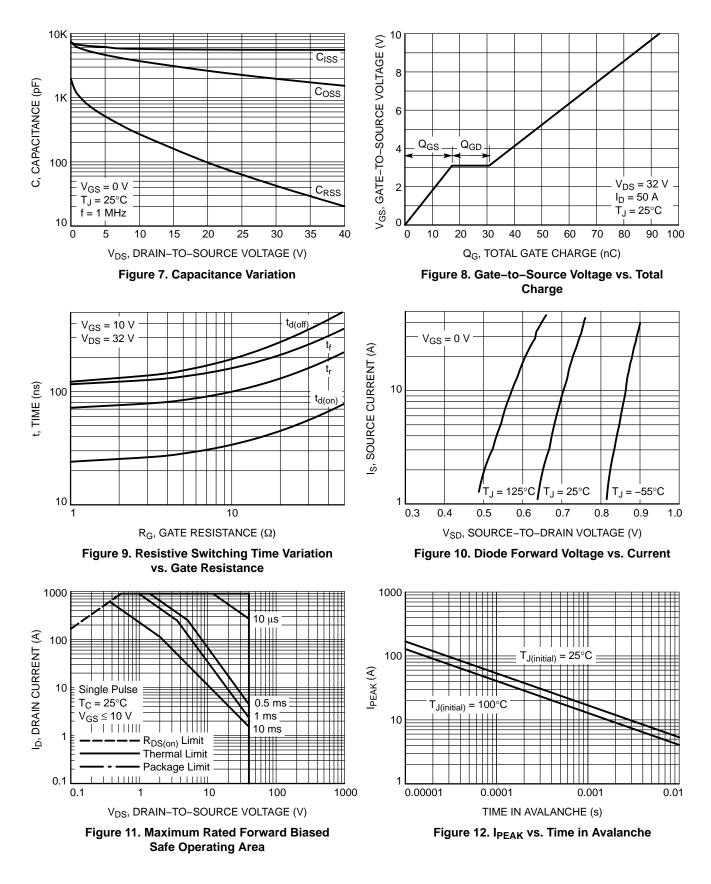
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, I <sub>D</sub> = 250 $\mu$ A		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				20		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V,$	$T_J = 25^{\circ}C$			10	
		$V_{DS} = 40 V$	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS}$	<sub>6</sub> = 20 V			100	nA
<b>ON CHARACTERISTICS</b> (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \ \mu A$		1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.3		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		1.5	1.8	mΩ
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		1	1.2	mΩ
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> =10 V, I <sub>D</sub> = 50 A			190		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE				-	-	
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			5600		pF
Output Capacitance	C <sub>OSS</sub>				2600		
Reverse Transfer Capacitance	C <sub>RSS</sub>				70		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 32 V; $I_{D}$ = 50 A			44		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 32 V; $I_{D}$ = 50 A			93		
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 32 V; I <sub>D</sub> = 50 A			9.4		nC
Gate-to-Source Charge	Q <sub>GS</sub>				17.2		
Gate-to-Drain Charge	Q <sub>GD</sub>				13.6		
Plateau Voltage	V <sub>GP</sub>				3.1		V
SWITCHING CHARACTERISTICS (Note 5	i)				-	-	
Turn–On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 32 V, I <sub>D</sub> = 50 A, R <sub>G</sub> = 2.5 Ω			24		ns
Rise Time	t <sub>r</sub>				72		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				122		
Fall Time	t <sub>f</sub>				116		
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	$V_{SD}$ $V_{CS} = 0.V$	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.76	1.2	\ <i>`</i>
			T <sub>J</sub> = 125°C		0.66		V
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 50 A			59		ns
Charge Time	ta				29		
Discharge Time	t <sub>b</sub>				30		
Reverse Recovery Charge	Q <sub>RR</sub>				43		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width  $\leq 300 \ \mu$ s, duty cycle  $\leq 2\%$ . 5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



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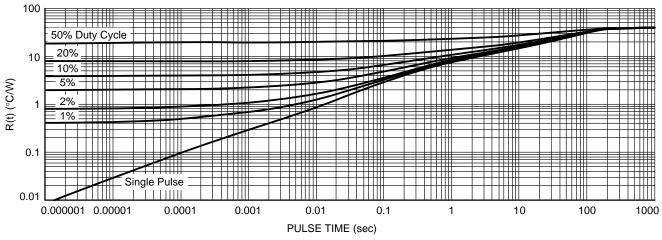


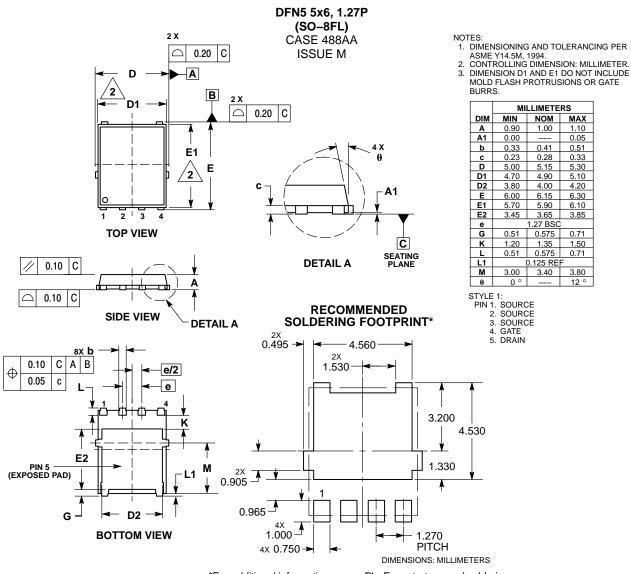
Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMFS5C426NLT1G	5C426L	DFN5 (Pb–Free)	1500 / Tape & Reel
NVMFS5C426NLWFT1G	426LWF	DFN5 (Pb–Free, Wettable Flanks)	1500 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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#### PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303–675–2176 or 800–344–3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative